

IN THE UNITED STATES ATENT AND TRADEMARK OFFICE

In re Patent Application of

Soichi Kobayashi et al.

Application No.: 10/632,928

Filed: August 4, 2003

For: SEMICONDUCTOR INTEGRATED

CIRCUIT CAPABLE OF TESTING WITH SMALL SCALE CIRCUIT

CONFIGURATION

MAIL STOP AMENDMENT

Group Art Unit: 2117

Examiner: SAQIB JAVAID

SIDDIQUI

Confirmation No.: 4942

AMENDMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In response to the Office Action dated July 10, 2007, the period for response to which having been extended by three months to January 10, 2008, please amend the above-identified patent application as follows.